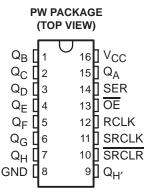
- Controlled Baseline
  - One Assembly/Test Site, One Fabrication Site
- Enhanced Diminishing Manufacturing Sources (DMS) Support
- Enhanced Product-Change Notification
- Qualification Pedigree<sup>†</sup>
- 2-V to 5.5-V V<sub>CC</sub> Operation
- Max t<sub>pd</sub> of 7.4 ns at 5 V
- Typical V<sub>OLP</sub> (Output Ground Bounce)
   <0.8 V at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C
- Typical V<sub>OHV</sub> (Output V<sub>OH</sub> Undershoot)
   >2.3 V at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C

† Component qualification in accordance with JEDEC and industry standards to ensure reliable operation over an extended temperature range. This includes, but is not limited to, Highly Accelerated Stress Test (HAST) or biased 85/85, temperature cycle, autoclave or unbiased HAST, electromigration, bond intermetallic life, and mold compound life. Such qualification testing should not be viewed as justifying use of this component beyond specified performance and environmental limits.

- Supports Mixed-Mode Voltage Operation on All Ports
- 8-Bit Serial-In, Parallel-Out Shift
- I<sub>off</sub> Supports Partial-Power-Down Mode Operation
- Shift Register Has Direct Clear



### description/ordering information

The SN74LV595A is an 8-bit shift register designed for 2-V to 5.5-V V<sub>CC</sub> operation.

This device contains an 8-bit serial-in, parallel-out shift register that feeds an 8-bit D-type storage register. The storage register has parallel 3-state outputs. Separate clocks are provided for both the shift and storage register. The shift register has a direct overriding clear  $(\overline{SRCLR})$  input, serial (SER) input, and a serial output for cascading. When the output-enable  $(\overline{OE})$  input is high, all outputs except  $Q_{H'}$  are in the high-impedance state.

Both the shift register clock (SRCLK) and storage register clock (RCLK) are positive-edge triggered. If both clocks are connected together, the shift register always is one clock pulse ahead of the storage register.

To ensure the high-impedance state during power up or power down,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The device is fully specified for partial-power-down applications using I<sub>off</sub>. The I<sub>off</sub> circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

### **ORDERING INFORMATION**

TA	PACKA	\GE‡	ORDERABLE PART NUMBER	TOP-SIDE MARKING
-40°C to 85°C	TSSOP - PW	Reel of 2000	SN74LV595AIPWREP	LV595EP

<sup>&</sup>lt;sup>‡</sup> Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



## SN74LV595A-EP **8-BIT SHIFT REGISTER** WITH 3-STATE OUTPUT REGISTERS SCLS568B – JANUARY 2004 – REVISED MAY 2004

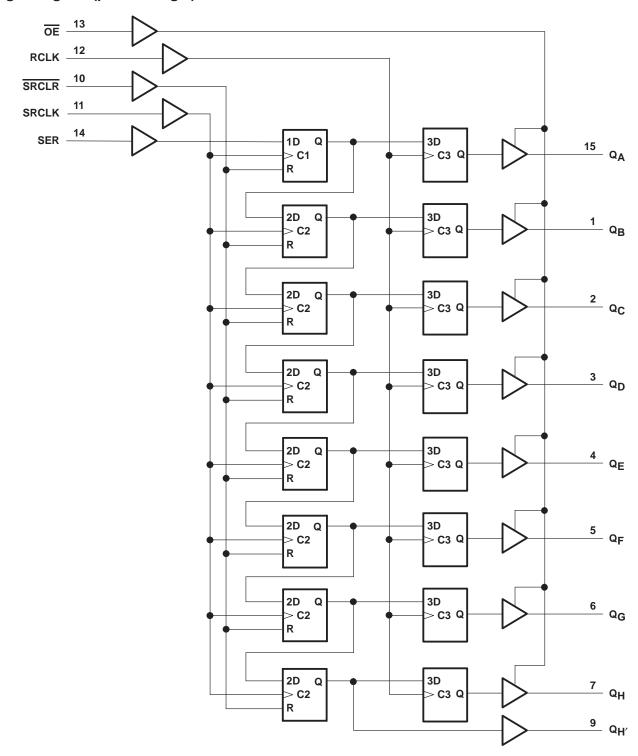
### **FUNCTION TABLE**

		INPUTS			FUNCTION
SER	SRCLK	SRCLR	RCLK	OE	FUNCTION
Х	Х	Х	Х	Н	Outputs Q <sub>A</sub> –Q <sub>H</sub> are disabled.
Х	Χ	X	Χ	L	Outputs Q <sub>A</sub> –Q <sub>H</sub> are enabled.
Х	Χ	L	Χ	Χ	Shift register is cleared.
L	1	Н	Х	Х	First stage of the shift register goes low. Other stages store the data of previous stage, respectively.
Н	1	Н	Х	Х	First stage of the shift register goes high. Other stages store the data of previous stage, respectively.
Х	$\downarrow$	Н	Х	Χ	Shift-register state is not changed.
Х	Χ	X	$\uparrow$	Χ	Shift-register data is stored in the storage register.
Х	Χ	Χ	$\downarrow$	Χ	Storage-register state is not changed.



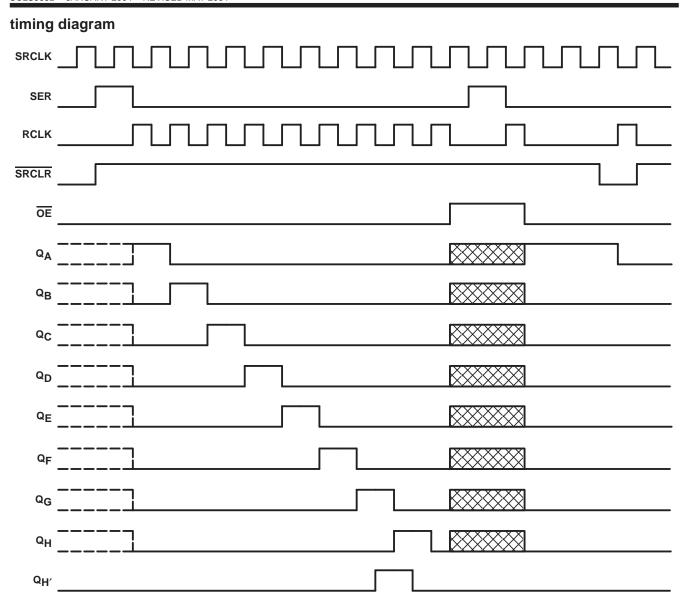
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## logic diagram (positive logic)





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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>	–0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)	–0.5 V to 7 V
Voltage range applied to any output in the high-impedance	
or power-off state, V <sub>O</sub> (see Note 1)	–0.5 V to 7 V
Output voltage range applied in the high or low state, VO (see Notes 1 and 2)	$\dots$ -0.5 V to V <sub>CC</sub> + 0.5 V
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0)	–20 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0)	–50 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )	±35 mA
Continuous current through V <sub>CC</sub> or GND	±70 mA
Package thermal impedance, $\theta_{JA}$ (see Note 3)	108°C/W
Storage temperature range, T <sub>stg</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output current ratings are observed.
  - 2. This value is limited to 5.5 V maximum.
  - 3. The package thermal impedance is calculated in accordance with JESD 51-7.

### recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
Vcc	Supply voltage		2	5.5	V
		V <sub>CC</sub> = 2 V	1.5		
.,	LPak Israel Construction	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	V <sub>CC</sub> ×0.7		, ,
$V_{IH}$	High-level input voltage	V <sub>CC</sub> = 3 V to 3.6 V	V <sub>CC</sub> ×0.7		V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	V <sub>CC</sub> × 0.7		
		V <sub>CC</sub> = 2 V		0.5	
V/	Law level input valtage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		$V_{CC} \times 0.3$	V
$V_{IL}$	Low-level input voltage	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$		$V_{CC} \times 0.3$	V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		$V_{CC} \times 0.3$	
٧ <sub>I</sub>	Input voltage		0	5.5	V
.,	Output wells as	High or low state	0	Vсс	.,
VO	Output voltage	3-state	0	5.5	V
		V <sub>CC</sub> = 2 V		-50	μΑ
	High lavel autout accept	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		-2	
ЮН	High-level output current	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$		-8	mA
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		-16	
		V <sub>CC</sub> = 2 V		50	μΑ
	Law law law at a war at	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		2	
lOL	Low-level output current	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$		8	mA
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		16	
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		200	
Δt/Δν	Input transition rise or fall rate	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$		100	ns/V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		20	
TA	Operating free-air temperature		-40	85	°C

NOTE 4: All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



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## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PAR	AMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	UNIT
		$I_{OH} = -50 \mu\text{A}$	2 V to 5.5 V	V <sub>CC</sub> -0.1			
		$I_{OH} = -2 \text{ mA}$	2.3 V	2			
	$Q_{H'}$	$I_{OH} = -6 \text{ mA}$	2.1/	2.48			V
VOH	Q <sub>A</sub> -Q <sub>H</sub>	$I_{OH} = -8 \text{ mA}$	3 V	2.48			V
	$Q_{H'}$	I <sub>OH</sub> = -12 mA	45.77	3.8			
	Q <sub>A</sub> -Q <sub>H</sub>	I <sub>OH</sub> = -16 mA	4.5 V	3.8			
		$I_{OL} = 50 \mu\text{A}$	2 V to 5.5 V			0.1	
		$I_{OL} = 2 \text{ mA}$	2.3 V			0.4	
<b>1</b> .,	$Q_{H'}$	$I_{OL} = 6 \text{ mA}$	0.1/			0.44	V
VOL	Q <sub>A</sub> -Q <sub>H</sub>	$I_{OL} = 8 \text{ mA}$	3 V			0.44	V
	$Q_{H'}$	$I_{OL} = 12 \text{ mA}$	45.77			0.55	
	Q <sub>A</sub> -Q <sub>H</sub>	$I_{OL} = 16 \text{ mA}$	4.5 V			0.55	
II		$V_I = 5.5 \text{ V or GND}$	0 to 5.5 V			±1	μΑ
loz		$V_O = V_{CC}$ or GND	5.5 V			±5	μΑ
ICC		$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			20	μΑ
I <sub>off</sub>		$V_I$ or $V_O = 0$ to 5.5 $V$	0			5	μΑ
Ci		$V_I = V_{CC}$ or GND	3.3 V		3.5		pF

# timing requirements over recommended operating free-air temperature range, $V_{CC}$ = 2.5 V $\pm$ 0.2 V (unless otherwise noted) (see Figure 1)

			$T_A = 2$	25°C			
			MIN	MAX	MIN	MAX	UNIT
		SRCLK high or low	7		7.5		
t <sub>W</sub> Pulse duration	RCLK high or low	7		7.5		ns	
		SRCLR low	6		6.5		
		SER before SRCLK↑	5.5		5.5		
١.	Oats un time a	SRCLK↑ before RCLK↑†	8		9		
t <sub>SU</sub> Setup time	Setup time	SRCLR low before RCLK↑	8.5		9.5		ns
		SRCLR high (inactive) before SRCLK↑	4		4		
th	Hold time	SER after SRCLK↑	1.5		1.5		ns

<sup>†</sup> This setup time allows the storage register to receive stable data from the shift register. The clocks can be tied together, in which case the shift register is one clock pulse ahead of the storage register.



## timing requirements over recommended operating free-air temperature range, $V_{CC}$ = 3.3 V $\pm$ 0.3 V (unless otherwise noted) (see Figure 1)

			T <sub>A</sub> = 2	25°C			
			MIN	MAX	MIN	MAX	UNIT
		SRCLK high or low	5.5		5.5		
t <sub>w</sub>	t <sub>w</sub> Pulse duration	RCLK high or low	5.5		5.5		ns
		SRCLR low	5		5		
		SER before SRCLK↑	3.5		3.5		
<b>1</b> .	Catura time	SRCLK↑ before RCLK↑†	8		8.5		
tsu	Setup time	SRCLR low before RCLK↑	8		9		ns
		SRCLR high (inactive) before SRCLK↑	3		3		
th	Hold time	SER after SRCLK↑	1.5	·	1.5		ns

This setup time allows the storage register to receive stable data from the shift register. The clocks can be tied together, in which case the shift register is one clock pulse ahead of the storage register.

## timing requirements over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

			$T_A = 2$	25°C				
			MIN	MAX	MIN	MAX	UNIT	
		SRCLK high or low	5		5			
t <sub>W</sub> Pulse duration	RCLK high or low	5		5		ns		
		SRCLR low	5.2		5.2			
		SER before SRCLK↑	3		3			
١.	Catus times	SRCLK↑ before RCLK↑†	5		5			
t <sub>su</sub>	Setup time	SRCLR low before RCLK↑	5		5		ns	
		SRCLR high (inactive) before SRCLK↑	2.5		2.5			
th	Hold time	SER after SRCLK↑	2		2		ns	

<sup>†</sup> This setup time allows the storage register to receive stable data from the shift register. The clocks can be tied together, in which case the shift register is one clock pulse ahead of the storage register.



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# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 2.5 V $\pm$ 0.2 V (unless otherwise noted) (see Figure 1)

DADAMETER	FROM	то	LOAD	T,	գ = 25°C	;		MAX	
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	UNIT
,			C <sub>L</sub> = 15 pF	65	80		45		N 41 1-
f <sub>max</sub>			C <sub>L</sub> = 50 pF	60	70		40		MHz
<sup>t</sup> PLH	DOLK	0 0			8.4	14.2	1	15.8	
<sup>t</sup> PHL	RCLK	Q <sub>A</sub> –Q <sub>H</sub>			8.4	14.2	1	15.8	
<sup>t</sup> PLH	CDCLK				9.4	19.6	1	22.2	
<sup>t</sup> PHL	SRCLK	$Q_{H'}$			9.4	19.6	1	22.2	
<sup>t</sup> PHL	SRCLR	$Q_{H'}$	C <sub>L</sub> = 15 pF		8.7	14.6	1	16.3	ns
<sup>t</sup> PZH	ŌE ŌE				8.2	13.9	1	15	
tPZL		Q <sub>A</sub> –Q <sub>H</sub>			10.9	18.1	1	20.3	
<sup>t</sup> PHZ		00			8.3	13.7	1	15.6	
tPLZ	OE	Q <sub>A</sub> –Q <sub>H</sub>			9.2	15.2	1	16.7	
<sup>t</sup> PLH	RCLK	0 . 0 .			11.2	17.2	1	19.3	
<sup>t</sup> PHL	RCLK	Q <sub>A</sub> –Q <sub>H</sub>			11.2	17.2	1	19.3	
tPLH	SDCI I/	0			13.1	22.5	1	25.5	
<sup>t</sup> PHL	SRCLK	Q <sub>H</sub> ′			13.1	22.5	1	25.5	
<sup>t</sup> PHL	SRCLR	$Q_{H'}$	$C_L = 50 pF$		12.4	18.8	1	21.1	ns
<sup>t</sup> PZH	<del></del>				10.8	17	1	18.3	
tPZL	ŌĒ ŌĒ				13.4	21	1	23	
<sup>t</sup> PHZ		00			12.2	18.3	1	19.5	
tPLZ	ÜE	Q <sub>A</sub> –Q <sub>H</sub>			14	20.9	1	22.6	



## SN74LV595A-EP **8-BIT SHIFT REGISTER** WITH 3-STATE OUTPUT REGISTERS SCLS568B - JANUARY 2004 - REVISED MAY 2004

# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 3.3 V $\pm$ 0.3 V (unless otherwise noted) (see Figure 1)

DADAMETER	FROM	то	LOAD	T,	4 = 25°C	;	MIN MA	14 A V		
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	UNIT	
			C <sub>L</sub> = 15 pF	80	120		70		N 41 1-	
f <sub>max</sub>			C <sub>L</sub> = 50 pF	55	105		50		MHz	
<sup>t</sup> PLH	DOLK	0 0			6	11.9	1	13.5		
<sup>t</sup> PHL	RCLK	$Q_A-Q_H$			6	11.9	1	13.5		
<sup>t</sup> PLH	CDCLK				6.6	13	1	15		
<sup>t</sup> PHL	SRCLK	Q <sub>H</sub> ′			6.6	13	1	15		
<sup>t</sup> PHL	SRCLR	Q <sub>H</sub> ′	C <sub>L</sub> = 15 pF		6.2	12.8	1	13.7	ns	
<sup>t</sup> PZH	<del></del>	0.0			6	11.5	1	13.5		
<sup>t</sup> PZL	ŌĒ	QA-QH	$Q_A-Q_H$			7.8	11.5	1	13.5	
<sup>t</sup> PHZ	ŌĒ				6.1	14.7	1	15.2		
tPLZ	OE	Q <sub>A</sub> -Q <sub>H</sub>			6.3	14.7	1	15.2		
<sup>t</sup> PLH	DOLK	0 0			7.9	15.4	1	17		
<sup>t</sup> PHL	RCLK	$Q_A-Q_H$			7.9	15.4	1	17		
<sup>t</sup> PLH	CDCLK	0			9.2	16.5	1	18.5		
<sup>t</sup> PHL	SRCLK	Q <sub>H</sub> ′			9.2	16.5	1	18.5		
<sup>t</sup> PHL	SRCLR	Q <sub>H</sub> ′	$C_{L} = 50 \text{ pF}$		9	16.3	1	17.2	ns	
<sup>t</sup> PZH	<del></del>		7		7.8	15	1	17		
<sup>t</sup> PZL	ŌĒ	Q <sub>A</sub> –Q <sub>H</sub>			9.6	15	1	17		
<sup>t</sup> PHZ		0 . 0	7		8.1	15.7	1	16.2		
<sup>t</sup> PLZ	ŌĒ	Q <sub>A</sub> –Q <sub>H</sub>			9.3	15.7	1	16.2		

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# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

DADAMETED	FROM	то	LOAD	T,	չ = 25°C	;	BAIN!	MAY	
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	UNIT
			C <sub>L</sub> = 15 pF	135	170		115		N 41 1-
f <sub>max</sub>			C <sub>L</sub> = 50 pF	120	140		95		MHz
tPLH	BOLK	0 0			4.3	7.4	1	8.5	
t <sub>PHL</sub>	RCLK	$Q_A$ – $Q_H$			4.3	7.4	1	8.5	
t <sub>PLH</sub>	CDCL K	0			4.5	8.2	1	9.4	
<sup>t</sup> PHL	SRCLK	Q <sub>H</sub> ′			4.5	8.2	1	9.4	
<sup>t</sup> PHL	SRCLR	Q <sub>H</sub> ′	C <sub>L</sub> = 15 pF		4.5	8	1	9.1	ns
<sup>t</sup> PZH	ŌE				4.3	8.6	1	10	
tPZL		$Q_A-Q_H$			5.4	8.6	1	10	
<sup>t</sup> PHZ		0 0			2.4	6	1	7.1	
tPLZ	ÜE	$Q_A-Q_H$			2.7	5.1	1	7.2	1
<sup>t</sup> PLH	RCLK	0 - 0 -			5.6	9.4	1	10.5	
<sup>t</sup> PHL	ROLK	$Q_A-Q_H$			5.6	9.4	1	10.5	
<sup>t</sup> PLH	CDCLK	0			6.4	10.2	1	11.4	
t <sub>PHL</sub>	SRCLK	Q <sub>H</sub> ′			6.4	10.2	1	11.4	
<sup>t</sup> PHL	SRCLR	Q <sub>H</sub> ′	C <sub>L</sub> = 50 pF		6.4	10	1	11.1	ns
<sup>t</sup> PZH	<del></del>				5.7	10.6	1	12	
tpZL	ŌĒ ŌĒ	$Q_A-Q_H$			6.8	10.6	1	12	
t <sub>PHZ</sub>		0. 0	1		3.5	10.3	1	11	
tPLZ	OE	Q <sub>A</sub> -Q <sub>H</sub>			3.4	10.3	1	11	

## noise characteristics, $V_{CC}$ = 3.3 V, $C_L$ = 50 pF, $T_A$ = 25°C (see Note 5)

	PARAMETER	MIN	TYP	MAX	UNIT
VOL(P)	Quiet output, maximum dynamic V <sub>OL</sub>		0.3		V
V <sub>OL</sub> (V)	Quiet output, minimum dynamic V <sub>OL</sub>		-0.2		V
VOH(V)	Quiet output, minimum dynamic VOH		2.8		V
VIH(D)	High-level dynamic input voltage	2.31			V
V <sub>IL(D)</sub>	Low-level dynamic input voltage			0.99	V

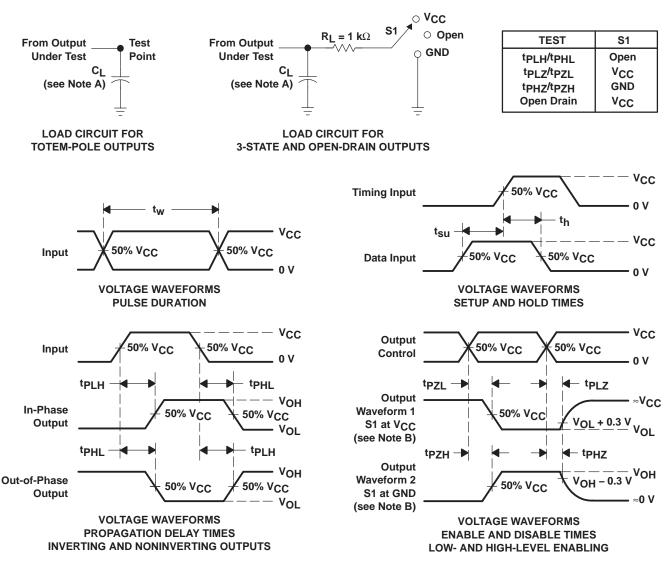
NOTE 5: Characteristics are for surface-mount packages only.

## operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CO	NDITIONS	VCC	TYP	UNIT
٠.	Daylor discination conscitones	C. F0 pF	f 40 MH-	3.3 V	111	~F
Cpd	Power dissipation capacitance	$C_L = 50 pF$ ,	f = 10 MHz	5 V	114	pF



#### PARAMETER MEASUREMENT INFORMATION



- NOTES: A.  $C_L$  includes probe and jig capacitance.
  - B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
  - C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_{O} = 50 \Omega$ ,  $t_{f} \leq$  3 ns,  $t_{f} \leq$  3 ns.
  - D. The outputs are measured one at a time, with one input transition per measurement.
  - E. tpLZ and tpHZ are the same as tdis.
  - F. tpzi and tpzH are the same as ten.
  - G. tpHL and tpLH are the same as tpd.
  - H. All parameters and waveforms are not applicable to all devices.

Figure 1. Load Circuit and Voltage Waveforms





### PACKAGE OPTION ADDENDUM

10-Dec-2020

#### PACKAGING INFORMATION

www.ti.com

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
SN74LV595AIPWREP	ACTIVE	TSSOP	PW	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	LV595EP	Samples
V62/04696-01XE	ACTIVE	TSSOP	PW	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	LV595EP	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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### **PACKAGE OPTION ADDENDUM**

10-Dec-2020

#### OTHER QUALIFIED VERSIONS OF SN74LV595A-EP:

• Automotive: SN74LV595A-Q1

NOTE: Qualified Version Definitions:

• Catalog - TI's standard catalog product

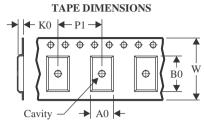
• Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

## **PACKAGE MATERIALS INFORMATION**

www.ti.com 3-Jun-2022

### TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

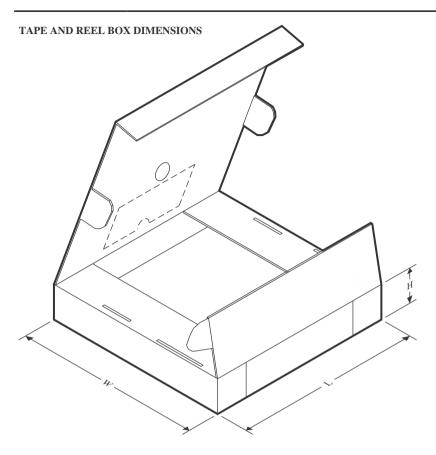


#### \*All dimensions are nominal

	Device	_	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ĺ	SN74LV595AIPWREP	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

## **PACKAGE MATERIALS INFORMATION**

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### \*All dimensions are nominal

Ì	Device	Package Type	Package Drawing	Pins SPQ		Length (mm)	Width (mm)	Height (mm)	
ı	SN74LV595AIPWREP	TSSOP	PW	16	2000	356.0	356.0	35.0	



SMALL OUTLINE PACKAGE



#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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